

Information Disclosure Statement
 USSN 10/627,405
 February 7, 2005
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| Form PTO-1449 (Modified) | ATTY DOCKET NO. B-5025NP 620801-2 | U.S. SERIAL NO. 10/627,405 |
| LIST OF PATENTS AND PUBLICATIONS STATEMENT | APPLICANTS André DeHon, et al. | |
| | FILING DATE July 24, 2003 | GROUP 2817 |

| U.S. PATENT DOCUMENTS | | | | | | |
|-----------------------|-----------------|------------|------|-------|----------|---|
| EXAMINER INITIAL | DOCUMENT NUMBER | ISSUE DATE | NAME | CLASS | SUBCLASS | FILING DATE OR 102(e) DATE IF APPROPRIATE |
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| FOREIGN PATENT DOCUMENTS | | | | | | |
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| | DOCUMENT NUMBER | ISSUE DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO |
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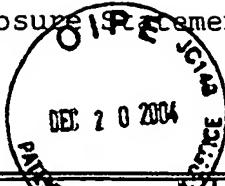
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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| SWC | DeHon, A., "Array-Based Architecture for FET-Based, Nanoscale Electronics," IEEE Transactions on Nanotechnology, Vol. 2, No. 1, pp. 23-32 (March 2003). |
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and do not consider. Include copy of this form with next communication to applicant.

Information Disclosure Statement
 USSN 10/627,405
 December 14, 2004
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| Form PTO-1449 (Modif. 9/99) | ATTY DOCKET NO. B-5025NP 620801-2 | U.S. SERIAL NO. 10/627,405 |
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U. S. PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | ISSUE DATE | NAME | CLASS | SUB-CLASS | FILING DATE or 102(e) DATE IF APPROPRIATE |
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| SWC | 6,383,784 B1 | 5/2002 | Smith | 435 | 91.2 | |
| SWC | 2002/0027819 A1 | 3/2002 | Tomanek et al. | 365 | 215 | |

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| | DOCUMENT NUMBER | ISSUE DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO |
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| SWC | 02/103753 A2 | 12/2002 | WO | | | |
| SWC | 2004/034467 A2 | 4/2004 | WO | | | |
| SWC | 2004/061859 A2 | 7/2004 | WO | | | |

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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